

1. Record Nr.	UNISA996216258403316
Autore	Bubert Henning
Titolo	Surface and Thin Film Analysis : A Compendium of Principles, Instrumentation and Applications
Pubbl/distr/stampa	Hoboken, : Wiley, 2011
ISBN	1-280-55760-5 9786610557608 3-527-60016-7
Edizione	[2nd ed.]
Descrizione fisica	1 online resource (559 p.)
Altri autori (Persone)	JenettHolger
Disciplina	530.4275 541.33
Soggetti	Thin films - Analysis - Surfaces Electron spectroscopy Spectrum analysis
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di contenuto	Surface and Thin Film Analysis: A Compendium of Principles, Instrumentation, and Applications; Contents; Preface to the First Edition; Preface to the Second Edition; List of Contributors; 1: Introduction; Part One: Electron Detection; 2: X-Ray Photoelectron Spectroscopy (XPS); 2.1 Principles; 2.2 Instrumentation; 2.2.1 Vacuum Requirements; 2.2.2 X-Ray Sources; 2.2.3 Synchrotron Radiation; 2.2.4 Electron Energy Analyzers; 2.2.5 Spatial Resolution; 2.3 Spectral Information and Chemical Shifts; 2.4 Quantification, Depth Profiling, and Imaging; 2.4.1 Quantification; 2.4.2 Depth Profiling 2.4.3 Imaging2.5 The Auger Parameter; 2.6 Applications; 2.6.1 Catalysis; 2.6.2 Polymers; 2.6.3 Corrosion and Passivation; 2.6.4 Adhesion; 2.6.5 Superconductors; 2.6.6 Semiconductors; 2.7 Ultraviolet Photoelectron Spectroscopy (UPS); References; 3: Auger Electron Spectroscopy (AES); 3.1 Principles; 3.2 Instrumentation; 3.2.1 Vacuum Requirements; 3.2.2 Electron Sources; 3.2.3 Electron-Energy Analyzers; 3.3 Spectral Information; 3.4 Quantification and Depth Profiling; 3.4.1 Quantification; 3.4.2 Depth Profiling; 3.5 Applications; 3.5.1 Grain Boundary Segregation; 3.5.2 Semiconductor Technology

3.5.3 Thin Films and Interfaces 3.5.4 Surface Segregation; 3.6 Scanning Auger Microscopy (SAM); References; 4: Electron Energy-Loss Spectroscopy (EELS) and Energy-Filtering Transmission Electron Microscopy (EFTEM); 4.1 Principles; 4.2 Instrumentation; 4.3 Qualitative Spectral Information; 4.3.1 Low-Loss Excitations; 4.3.2 Ionization Losses; 4.3.3 Fine Structures; 4.4 Quantification; 4.5 Imaging of Element Distribution; 4.6 Summary; References; 5: Low-Energy Electron Diffraction (LEED); 5.1 Principles and History; 5.2 Instrumentation; 5.3 Qualitative Information; 5.3.1 LEED Pattern 5.3.2 Spot Profile Analysis 5.3.3 Applications and Restrictions; 5.4 Quantitative Structural Information; 5.4.1 Principles; 5.4.2 Experimental Techniques; 5.4.3 Computer Programs; 5.4.4 Applications and Restrictions; 5.5 Low-Energy Electron Microscopy; 5.5.1 Principles of Operation; 5.5.2 Applications and Restrictions; References; 6: Other Electron-Detecting Techniques; 6.1 Ion (Excited) Auger Electron Spectroscopy (IAES); 6.2 Ion Neutralization Spectroscopy (INS); 6.3 Inelastic Electron Tunneling Spectroscopy (IETS); Reference; Part Two: Ion Detection  
7: Static Secondary Ion Mass Spectrometry (SSIMS) 7.1 Principles; 7.2 Instrumentation; 7.2.1 Ion Sources; 7.2.2 Mass Analyzers; 7.2.2.1 Quadrupole Mass Spectrometers; 7.2.2.2 Time-of-Flight Mass Spectrometry (TOF-MS); 7.3 Quantification; 7.4 Spectral Information; 7.5 Applications; 7.5.1 Oxide Films; 7.5.2 Interfaces; 7.5.3 Polymers; 7.5.4 Biosensors; 7.5.5 Surface Reactions; 7.5.6 Imaging; 7.5.7 Ultra-Shallow Depth Profiling; References; 8: Dynamic Secondary Ion Mass Spectrometry (SIMS); 8.1 Principles; 8.1.1 Compensation of Preferential Sputtering; 8.1.2 Atomic Mixing 8.1.3 Implantation of Primary Ions

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Sommario/riassunto

Surveying and comparing all techniques relevant for practical applications, this second edition of a bestseller is a vital guide to this hot topic in nano- and surface technology. Completely revised and updated, sections include electron, ion and photon detection, as well as scanning microscopy, while new chapters have been added to cover such recently developed techniques as SNOM, SERS, and laser ablation. Over 500 references and a list of equipment suppliers make this a rapid reference for materials scientists, analytical chemists, and those working in the biotechnological industry.

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2. Record Nr.	UNINA9910963629603321
Titolo	Assessing teacher effectiveness : developing a differentiated model // Jim Campbell ... [et al.]
Pubbl/distr/stampa	London ; New York, : RoutledgeFalmer, 2004
ISBN	1-134-40722-X 0-415-30479-2 1-134-40723-8 1-280-04948-0 0-203-40370-3
Edizione	[1st ed.]
Descrizione fisica	1 online resource (241 p.)
Altri autori (Persone)	CampbellR. J
Disciplina	371.14/4
Soggetti	Teachers - Rating of Teacher effectiveness
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references (p. [196]-219) and index.
Nota di contenuto	The background to teacher effectiveness research -- Towards a differentiated model -- Values and policy implications -- Differentiated teacher effectiveness research: the model in practice.
Sommario/riassunto	How can we really evaluate teacher effectiveness?Systems of teacher appraisal and evaluation are being created across the world in order to monitor and assess teacher performance. But do the models used really give a fair evaluation?Based on international research, the authors argue that teacher effectiveness is too narrowly conceptualised and methods of measuring it are not attuned to the real contexts in which teachers work. They propose a model of differential teacher effectiveness which takes into account that:* teachers may be more effective with some categories of

3. Record Nr.	UNINA9910139308203321
Titolo	Forschung
Pubbl/distr/stampa	Weinheim, Fed. Rep. of Germany, : [Deutsche Forschungsgemeinschaft], : Wiley-VCH Verlag
ISSN	1522-2357
Descrizione fisica	1 online resource
Soggetti	<p>Science</p> <p>Engineering - Research</p> <p>Research - Germany (West)</p> <p>Research - Germany</p> <p>Recherche technique - Periodiques</p> <p>Recherche - Allemagne (Ouest) - Periodiques</p> <p>Sciences</p> <p>Recherche technique</p> <p>Recherche - Allemagne (Ouest)</p> <p>Recherche - Allemagne</p> <p>Research</p> <p>Enginyeria</p> <p>Investigació</p> <p>periodicals.</p> <p>Periodicals.</p> <p>Periodiques.</p> <p>Revistes electròniques.</p> <p>Germany</p> <p>Germany (West)</p>
Lingua di pubblicazione	Tedesco
Formato	Materiale a stampa
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Note generali	<p>Refereed/Peer-reviewed</p> <p>Published: Bonn : Harald Boldt Verlag, 1979-; published: Weinheim, Fed. Rep. of Germany : [Deutsche Forschungsgemeinschaft] : Wiley-VCH Verlag GmbH, &lt;2001-&gt;</p>

